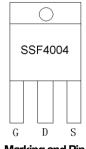
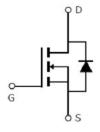


Main Product Characteristics

V _{DSS}	40V
R _{DS} (on)	2.3mΩ (typ.)
I _D	180A ①







TO-220

Marking and Pin
Assignment

Schematic Diagram

Features and Benefits

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



Description

SSF4004S utilizes the latest processing techniques to achieve high cell density and reduces on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating

Symbol	Parameter	Max.	Units	
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V(Silicon Limited)	180 ①		
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	120 ①	^	
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V(Package Limited)	75	A	
I _{DM}	Pulsed Drain Current ②	710		
P _D @TC = 25°C	Power Dissipation ③	200	W	
PD @ 10 = 25 C	Linear Derating Factor	1.3	W/°C	
V _{DS}	Drain-Source Voltage	40	V	
V _{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy @ L=0.3mH		mJ	
I _{AS}	Avalanche Current @ L=0.3mH	80	А	
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +175	°C	





Thermal Resistance

Symbol	Characteristics	Тур.	Max.	Units
R _{θJC}	Junction-to-case ③	_	0.75	°CM
$R_{\theta JA}$	Junction-to-ambient (t \leq 10s) (4)	_	62	°CM

Electrical Characteristics $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	40	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
D	Static Drain-to-Source on-resistance		2.3	4	mΩ	$V_{GS} = 10V, I_D = 75A$
R _{DS(on)}	Static Diam-to-Source on-resistance	_	4.1	_	11152	T _J = 125°C
V _{GS(th)}	Gate threshold voltage	2	_	4	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
V GS(th)	Gate tilleshold voltage	_	2.1	_	v	T _J = 125°C
	Drain to Source leakage current	_	_	1		$V_{DS} = 40V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source leakage current	_	_	50	μA	T _J = 125°C
	Cata to Source forward looked	_	_	100	n ^	V _{GS} = 20V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -20V
Qg	Total gate charge	_	278	_		I _D = 75A,
Q _{gs}	Gate-to-Source charge	_	41	_	nC	V _{DS} =32V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	119	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	71	_		
t _r	Rise time	_	34	_		V _{GS} =10V, V _{DS} =20V,
t _{d(off)}	Turn-Off delay time	_	131	_	ns	$R_{GEN}=3\Omega, I_D=1.3A$
t _f	Fall time	_	106	_		
C _{iss}	Input capacitance	_	12968	_		$V_{GS} = 0V$
Coss	Output capacitance	_	940	_	pF	V _{DS} = 40V
C _{rss}	Reverse transfer capacitance	capacitance — 905 —		f = 1MHz		

Source-Drain Ratings and Characteristics

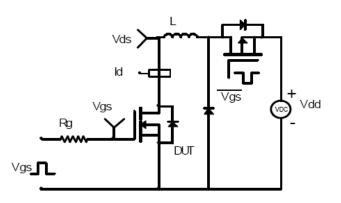
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current	_	_	75 ①	А	MOSFET symbol
	(Body Diode) Pulsed Source Current					showing the integral reverse
I _{SM}	(Body Diode)	_	_	750	А	p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	I _S =30A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	28	_	nS	$T_J = 25^{\circ}C, I_F = 70A,$
Q _{rr}	Reverse Recovery Charge	_	20	_	nC	di/dt = 100A/μs

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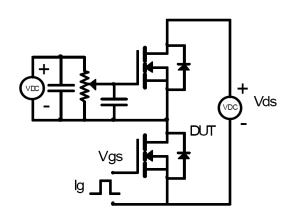


Test circuits and Waveforms

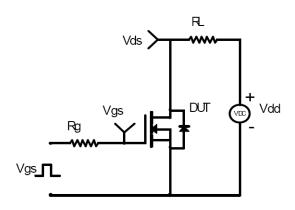
EAS Test Circuit



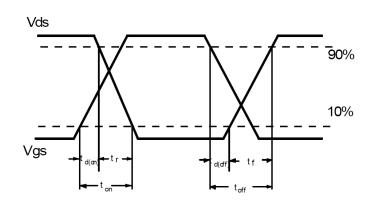
Gate charge test circuit



Switching Time Test Circuit



Switching Waveforms

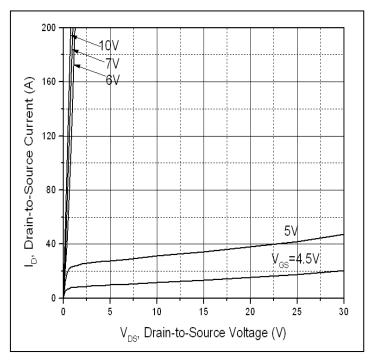


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\texttt{9JA}}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



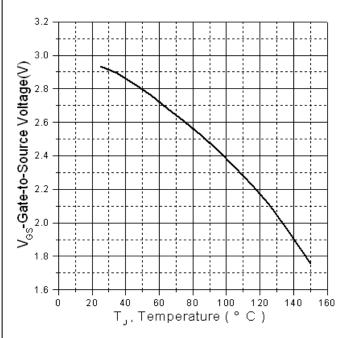


Figure 1.Typical Output Characteristics

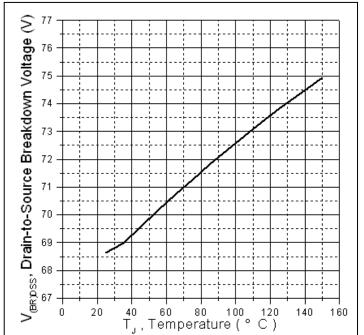


Figure 3. Drain-to-Source Breakdown Voltage Vs.

Case Temperature

Figure 2. Gate to source cut-off voltage

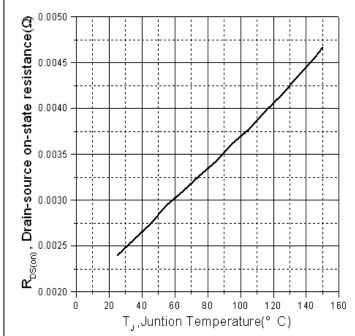
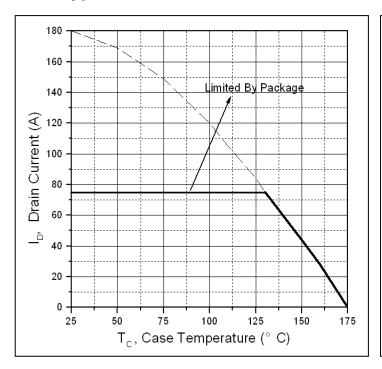


Figure 4.Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



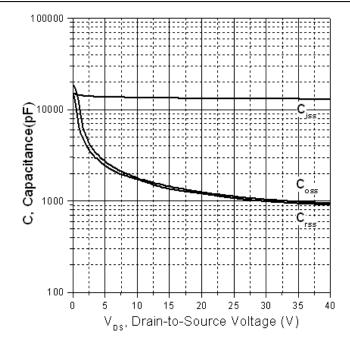


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

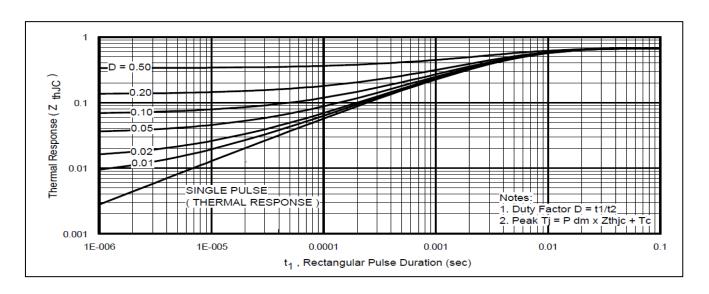
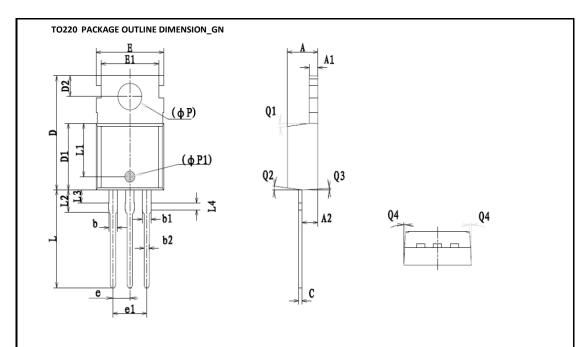


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Cumala al	Dime	nsion In Millin	neters	Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
А	4.400	4.550	4.700	0.173	0.179	0.185	
A1	1.270	1.300	1.330	0.050	0.051	0.052	
A2	2.240	2.340	2.440	0.088	0.092	0.096	
b	=	1.270	-	-	0.050	-	
b1	1.270	1.370	1.470	0.050	0.054	0.058	
b2	0.750	0.800	0.850	0.030	0.031	0.033	
С	0.480	0.500	0.520	0.019	0.020	0.021	
D	15.100	15.400	15.700	0.594	0.606	0.618	
D1	8.800	8.900	9.000	0.346	0.350	0.354	
D2	2.730	2.800	2.870	0.107	0.110	0.113	
Е	9.900	10.000	10.100	0.390	0.394	0.398	
E1	-	8.700	-	-	0.343	-	
ΦР	3.570	3.600	3.630	0.141	0.142	0.143	
ФР1	1.400	1.500	1.600	0.055	0.059	0.063	
е		2.54BSC		0.1BSC			
e1		5.08BSC			0.2BSC		
L	13.150	13.360	13.570	0.518	0.526	0.534	
L1		7.35REF	-		0.29REF		
L2	2.900	3.000	3.100	0.114	0.118	0.122	
L3	1.650	1.750	1.850	0.065	0.069	0.073	
L4	0.900	1.000	1.100	0.035	0.039	0.043	
Q1	5 ⁰	7 ⁰	90	5 ⁰	7 ⁰	90	
Q2	5 ⁰	7 ⁰	90	5 ⁰	7 ⁰	90	
Q3	5 ⁰	7 ⁰	90	5°	7 ⁰	90	
Q4	1 ⁰	3 ⁰	5 ⁰	1 ⁰	3 ⁰	5 ⁰	

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Ordering and Marking Information

Device Marking: SSF4004

Package (Available)
TO-220
Operating Temperature Range
C: -55 to 175 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Туре	Tube	Box	Box	Boxes/Carton	Box
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =150℃ @ 80% of	168 hours	3 lots x 77 devices
Temperature	Max V _{DSS} /V _{CES} /VR	500 hours	
Reverse		1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			





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